



A surface refractive index scanning system and method.

Kristensen, Anders; Vannahme, Christoph; Dufva, Martin

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(71) Applicant: **DANMARKS TEKNISKE UNIVERSITET**
[DK/DK]; Anker Engelundsvej 1, Bygning 101A, DK-
2800 Lyngby (DK).

(72) Inventors: **KRISTENSEN, Anders**; Harsdorffsvej 6B,
st.tv., DK-1874 Frederiksberg C (DK). **VANNAHME,**
Christoph; Ordrupvej 75, 4.th., DK-2920 Charlottenlund
(DK). **DUFVA, Martin**; Granvænget 3, DK-3100 Horn-
bæk (DK).

(74) Agent: **PLOUGMANN & VINGTOFT A/S**; Rued Lang-
gaards Vej 8, 2300 Copenhagen S (DK).

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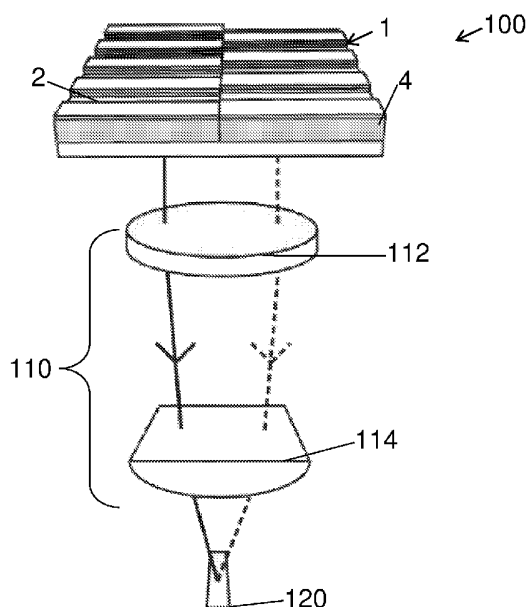


FIG. 2

(57) Abstract: The invention relates to a surface refractive index scanning system for characterization of a sample. The system comprises a grating device for holding or receiving the sample, the device comprising at least a first grating region having a first grating width along a transverse direction, and a second grating region having a second grating width in the transverse direction. The first grating region and the second grating region are adjacent in the transverse direction, wherein the first grating region has a grating period Λ_1 in a longitudinal direction, and the second grating region has a grating period Λ_2 in the longitudinal direction, where the longitudinal direction is orthogonal to the transverse direction. A grating period spacing $\Delta\Lambda = \Lambda_1 - \Lambda_2$ is finite. Further, the first and second grating periods are chosen to provide optical resonances for light respectively in a first wavelength band and a second wavelength band, light is being emitted, transmitted, or reflected in an out-of-plane direction, wherein the first wavelength band and the second wavelength band are at least partially non-overlapping in wavelength. The system further comprises a light source for illuminating at least a part of the grating device with light at an illumination wavelength band. Additionally, the system comprises an imaging system for imaging the emitted, transmitted or reflected light from the grating device. The imaging system comprises an optical element, such as a cylindrical lens or a bended mirror, configured for focusing light in a transverse direction and for being invariant in an orthogonal transverse direction, the optical element being oriented such that the longitudinal direction of the grating device is oriented to coincide with the invariant direction of the optical element, and an imaging spectrometer comprising

an entrance slit having a longitudinal direction oriented to coincide with the invariant direction of the optical element. The imaging spectrometer further comprises a 2-dimensional image sensor. The invention further relates to a method.



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A SURFACE REFRACTIVE INDEX SCANNING SYSTEM AND METHOD

FIELD OF THE INVENTION

The present invention relates to optical characterization of a sample. More
5 specifically, the invention relates to a surface refractive index scanning system.

BACKGROUND OF THE INVENTION

US 8,268,637 B2 discloses label-free biosensors based upon distributed feedback
10 (DFB) laser. In one configuration, the DFB laser comprises a replica-molded, one-
or two-dimensional dielectric grating coated with a laser dye-doped polymer as a
gain medium. The laser dye or other active material in the active layer is pumped
via an external optical source. The stimulated emission wavelength of the laser
dye is modulated, i.e. shifted, by the adsorption of biomolecules on the DFB laser
15 biosensor's surface. The reference does not teach a spatially resolved
measurement of the sample.

Hence, an improved surface refractive index detecting system would be
advantageous, and in particular a system providing a spatially resolved
20 measurement of the refractive index would be advantageous.

OBJECT OF THE INVENTION

It is a further object of the present invention to provide an alternative to the prior
25 art.

In particular, it may be seen as an object of the present invention to provide a
surface refractive index scanning system that solves the above mentioned
problems of the prior art with providing a 2-dimensional spatially resolved
30 measurement.

It may be seen as a further object of the present invention to provide a surface
refractive index scanning system that allows for time- and spatially resolved
measurements, preferably in a non-scanning fashion.

SUMMARY OF THE INVENTION

Thus, the above-described object and several other objects are intended to be obtained in a first aspect of the invention by providing a surface refractive index scanning system for characterization of a sample. The system comprises a grating device for holding or receiving the sample, the device comprising at least a first grating region having a first grating width along a transverse direction, and a second grating region having a second grating width in the transverse direction. The first grating region and the second grating region are adjacent in the transverse direction, wherein the first grating region has a grating period Λ_1 in a longitudinal direction being orthogonal to the transverse direction, and the second grating region has a grating period Λ_2 in the longitudinal direction. A grating period spacing $\Delta\Lambda = \Lambda_1 - \Lambda_2$ is chosen to be finite. Further, the first and second grating periods are chosen to provide optical resonances for light respectively in a first wavelength band and a second wavelength band, light is being emitted, transmitted, or reflected in an out-of-plane direction, wherein the first wavelength band and the second wavelength band are at least partially non-overlapping in wavelength. The system further comprises a light source for illuminating at least a part of the grating device with light at an illumination wavelength band.

Additionally, the system comprises an imaging system for imaging the emitted, transmitted or reflected light from the grating device. The imaging system comprises an optical element configured for focusing light in a transverse direction and for being invariant in an orthogonal transverse direction, the optical element being oriented such that the longitudinal direction of the grating device is oriented to coincide with an invariant direction of the optical element, and an imaging spectrometer comprising an entrance slit having a longitudinal direction oriented to coincide with the invariant direction of the optical element. In this way, a spatially resolved characterization of the refractive index of a sample on a surface of the grating device may be obtained without physically scanning the grating device or the optical components, as will be described herein below. Light recorded from the grating regions will be resonant light, i.e. having a wavelength that lies within a wavelength band around a wavelength that satisfies a resonance condition in a grating region. Since the resonance condition of the grating depends on the refractive indices of high-index and low-index grating elements and refractive index of the material present on the surface, a change in refractive

index on the surface is immediately apparent as a change in resonance wavelength, i.e. a wavelength shift of the resonance peak. The optical element is adjusted to focus light from the grating regions onto the entrance slit, to maximize optical coupling. The imaging spectrometer then acts to resolve and

5 record a spectrum for each position along the entrance slit, corresponding to each position along the longitudinal direction of the grating device. Thus, the imaging spectrometer will spatially resolve spectral responses along the longitudinal direction of the grating device. The system ensures that a spectral response from the first grating region will be imaged along a detector line in the imaging

10 spectrometer, and a spectral response from the second grating region will be imaged along the same detector line in the imaging spectrometer. Since each of the first and second grating regions are configured to give optical resonances at different wavelengths, a spectrum recorded for one position in the longitudinal direction will in general show a first resonance peak corresponding to a response

15 from the first grating region, and a second resonance peak corresponding to the second grating region. The grating period spacing $\Delta\lambda$ should be chosen to spectrally separate the resonance peak from the first grating region from the resonance peak from the second grating region, also accounting for the resonance wavelength shift possibly arising from the refractive index change depending on

20 the sample. By ensuring that the first resonance peak and the second resonance peak are well-separated in wavelength, the response may thus also be spatially resolved in the transverse direction. By detecting the peak center wavelengths and monitoring for any shifts in these wavelengths, refractive index changes in the sample may be detected in a spatially resolved manner. The spatial

25 measurement resolution of the refractive index image will be given by the number and width of the grating regions in the transverse direction.

The invention is particularly suited for fluid samples, sample solutions, or samples suspended in a fluid.

30

In one embodiment of the invention, the optical element is a cylindrical lens.

In an alternative embodiment of the invention, the optical element is a bended mirror.

In the context of this specification, an orientation/direction of a first device being oriented to coincide with an orientation/direction of a second device is to be understood such that the orientation/direction of the first device when imaged onto the second device by any optical elements between the first and second
5 devices is such that the imaged orientation/direction coincide with the physical orientation/direction of the second device. Thus, e.g. a mirror folding the optical path is irrelevant in this regard.

In an embodiment of the surface refractive index scanning system, the grating
10 device comprises multiple structured regions, including the first grating region and the second grating region, such as a number of structured regions in the range 2-100, or 10-80, or even 20-50, wherein each of the grating regions are arranged to provide optical resonances for light respectively in corresponding wavelength
15 bands, light is being emitted, transmitted, or reflected in an out-of-plane direction, the corresponding wavelength bands being at least partially non-overlapping. In this way, the spatial measurement resolution in the transverse direction may be increased.

In an embodiment of the surface refractive index scanning system, the first
20 structured region and/or the second structured region are configured as a second order distributed Bragg reflector (DBR) for providing the optical resonance. In an alternative embodiment, the optical resonance is provided by a photonic crystal structure.

25 In an alternative embodiment, the optical resonance is provided by guided mode resonance filter (GMRF).

In an alternative embodiment, the optical resonance is provided by a plasmonic structure.

30

In an alternative embodiment, the optical resonance is provided by a nano-hole array.

In an embodiment of the surface refractive index scanning system, the grating
35 device comprises a light-emitting material having an emission spectrum, wherein

first structured region and the second structured region are configured such that the first wavelength range and the second wavelength range at least partially fall within the emission spectrum of the light-emitting material. In this way, the grating device is an active device that may be made to lase, with lasing
5 wavelengths being dependent on the refractive indices at the different positions of the device. This is advantageous so as to provide narrow resonance peaks and to increase the received power levels from each position.

In an embodiment of the surface refractive index scanning system, the grating
10 period spacing $\Delta\lambda$ between two adjacent grating regions is in the range 0.05nm-10nm, such as in the range 0.1nm-5nm, or even in the range 0.5nm-2nm. A grating period spacing in this region is particularly advantageous for resolving the generally narrow resonance peaks that result in the active grating device, while also ensuring reasonable spectral bandwidth-efficiency of the whole device. This is
15 a trade-off in that the resonance peaks must be spectrally well-separated to provide the transverse spatial resolution of the sample, i.e. have a sufficiently large $\Delta\lambda$, while the overall bandwidth of the device should be kept as small as possible, to ensure that the whole bandwidth range may be kept within the emission spectrum of the light-emitting material. Another limiting factor for the
20 choice of grating period spacing, which also applies to passive grating devices (as further discussed below), is that the spectral resolving bandwidth of the spectrometer should encompass the resonance peaks from all grating regions, while the spectrometer wavelength resolution should be able to resolve the individual peaks sufficiently to enable calculation of the center wavelengths
25 associated with each peak.

In an embodiment of the surface refractive index scanning system, the light-emitting material is or comprises a dye-doped material.

30 In an embodiment of the surface refractive index scanning system, the dye-doped material comprises a polymer.

In an embodiment of the surface refractive index scanning system, the grating device is a passive structure for reflecting or transmitting light in the wavelength
35 ranges.

In an embodiment of the surface refractive index scanning system, the grating period spacing $\Delta\Lambda$ between two adjacent grating regions is in the range 0.5nm-500nm, such as about 5nm-200nm, or even in the range 10nm-100nm.

- 5 In an embodiment of the surface refractive index scanning system, the system further comprises an optical gain material and a first cavity end reflector, and wherein the grating device is arranged as a second cavity end reflector, the gain material being disposed between the first cavity end reflector and the second cavity end reflector in an external cavity laser configuration.

10

In an embodiment of the surface refractive index scanning system, the system is or comprises a microscope system.

- According to a second aspect of the invention, the above-described object and
15 several other objects are intended to be obtained by a method of acquiring a surface refractive index image of a sample. The method comprises providing a grating device for holding the sample. The device comprises at least a first grating region having a first grating width along a transverse direction, and a second grating region having a second grating width in the transverse direction. The first
20 grating region and the second grating region are adjacent in the transverse direction. The first grating region has a grating period Λ_1 in a longitudinal direction, the longitudinal direction being orthogonal to the transverse direction, and the second grating region has a grating period Λ_2 in the longitudinal direction. The grating periods are selected such that a grating period spacing $\Delta\Lambda = \Lambda_1 - \Lambda_2$ is
25 finite, the first and second grating periods are furthermore chosen to provide optical resonances for light respectively in a first wavelength band and a second wavelength band. The resonant light is emitted, transmitted, or reflected in an out-of-plane direction, wherein the first wavelength band and the second wavelength band are at least partially non-overlapping in wavelength. The method
30 further comprises positioning the sample to be characterized onto the grating device so as to come into contact with the first and/or the second grating region, and illuminating at least a part of the grating device with light at an illumination wavelength band. Additionally, the method comprises imaging the emitted, transmitted or reflected light from the grating device with an imaging system into
35 a 2-dimensional raw image. The imaging system comprises an optical element,

configured for focusing light in a first transverse direction and for being invariant in an orthogonal transverse direction, wherein the optical element is oriented such that the longitudinal direction of the grating device is oriented to coincide with an invariant direction of the optical element. The imaging system additionally

5 comprises an imaging spectrometer that comprises an entrance slit having a longitudinal direction oriented to coincide with the invariant direction of the optical element. The imaging spectrometer further comprises a 2-dimensional image sensor, oriented along the longitudinal direction of the entrance slit. Finally, the method comprises processing the 2-dimensional raw image to obtain a 2-

10 dimensional map of refractive index change of the sample at the grating regions, where the processing utilizes that each row of pixels in the raw image perpendicular to the longitudinal direction of the entrance slit contains spectrally resolved resonance peaks for each grating region, each resonance peak corresponding to a position along the transverse direction of the grating device,

15 and positions in the raw image along the longitudinal direction translates directly to positions along the longitudinal direction of the grating device.

In an embodiment of the method according to the invention, the step of processing the image comprises tracking changes in spectral positions of the

20 resonance peaks to provide a time-resolved image of refractive index changes in the sample.

In an embodiment of the method according to the invention, processing the 2-dimensional raw image comprises for each row of pixels perpendicular to the

25 longitudinal direction of the entrance slit, detect peak positions in pixels for resonance peaks in the row associated with each grating region. Convert each peak position in pixels to a peak wavelength value of resonance. Calculate a wavelength shift for each of the peak wavelength values of resonance with regards to reference peak values corresponding to the grating device without the

30 sample present. Finally, calculate refractive index values from the wavelength shifts.

In an embodiment of the method, finding the peak position in pixels for each of the grating region comprises finding a peak pixel as a pixel with a highest

35 intensity reading within a range of pixels associated with that grating region. The

method further comprising calculating the peak position in pixels from a range of pixels around the peak pixel using a numerical method. In the paper Vannahme, *et. al*, Laser Photonics Rev., 1-7 (2013), DOI 10.1002/lpor.201300083, the present inventors have in section 2.5 thereof described data processing of a single
5 peak in spectrometer data. This paper, in particular section 2.5, is hereby incorporated by reference, for at least the purpose of two methods of finding peak wavelength positions.

In an embodiment of the method, the numerical method is a center of mass
10 calculation.

In an embodiment of the method, the numerical method is a function fit, such as a Lorentzian fit.

15 In alternative embodiments of the method, pixel values are converted to wavelength values before finding the peak positions.

In one such embodiment, finding the peak wavelength position comprises finding a peak intensity wavelength value for the grating region in question, and finding
20 the peak wavelength by a weighted fit, such as a center of mass calculation or a Lorentzian fit. Thus, this embodiment is analogous to the above-mentioned embodiment, except that calculations are performed on wavelength values, rather than pixel values.

25 The first and second aspects of the present invention may each be combined with any of the other aspects. These and other aspects of the invention will be apparent from and elucidated with reference to the embodiments described hereinafter.

30 BRIEF DESCRIPTION OF THE FIGURES

The surface refractive index scanning system according to the invention will now be described in more detail with regard to the accompanying figures. The figures show one way of implementing the present invention and is not to be construed

as being limiting to other possible embodiments falling within the scope of the attached claim set.

Figure 1 illustrates a grating device as comprised by the inventive system.

5 Figure 2 illustrates a simplified setup according to the invention.

Figure 3 illustrates an embodiment of the surface refractive index scanning system according to the invention.

Figure 4 illustrates an embodiment of the surface refractive index scanning system as arranged in a passive photonic crystal configuration according to the
10 invention.

Figure 5 illustrates an embodiment of the surface refractive index scanning system as arranged in an external cavity laser configuration according to the invention.

15 DETAILED DESCRIPTION OF AN EMBODIMENT

Figure 1 shows a grating device 1 as comprised by the inventive system. Here, two grating regions are illustrated, i.e. the first 2 and the second 4 region, having a grating period Λ_1 and Λ_2 , respectively. The grating period spacing between the
20 two grating regions $\Delta\Lambda$ should be chosen to spectrally separate the resonance from the first grating region from the resonance from the second grating region. Preferably the grating period should also be selected to minimize the bandwidth requirement of the whole grating device 1. In an embodiment, the grating device comprises a glass substrate 6, onto which is deposited a polymer-containing layer
25 8. The polymer-containing layer 8 may be doped with an active material, such as a dye for use in active embodiments of the inventive system. Alternatively, the polymer-containing layer 8 may be passive for use in passive embodiments. Finally, the grating device 1 preferably comprises a high refractive index layer, e. g. a TiO_2 -layer or a Ta_2O_5 -layer 10 on a top side of the device, which acts to
30 increase an optical overlap between a resonant light field within a grating region and a fluid sample put in contact with the top side of the device.

An example of a grating device as fabricated by the inventors, was made using a 4 inch Borofloat glass wafer as substrate. The glass wafer had a thickness of
35 500 μ m, but could in general have a thickness in the range of about 50 μ m–2mm.

An alternative embodiment could also be made in a plastic material such as COC, or in a different glass. The polymer-containing layer was formed as a dye doped thin film, or more specifically as a Pyrromethene 597 dopedOrmocomp-layer, having a thickness of 400nm. In general the polymer-containing layer could have
5 the thickness in the range of about 200nm–500nm, and could also be made in other material, such as poly-methyl methacrylate (PMMA) or SU8. Finally, the example device comprised a high index layer fabricated as an ion beam evaporated TiO₂-layer, with a thickness of 25nm (possible thickness range of about 0nm–400nm).

10

In the example device, 40 grating regions were made, with grating widths of 25μm. The grating periods Λ_i were chosen in the range $\Lambda_i = 351nm \dots 391nm$, with a constant grating period spacing $\Delta\Lambda = 1nm$ to result in resonances in the wavelength range $\lambda \sim 540nm - 600nm$.

15

In another example device, 11 grating regions were made, with grating widths of 90μm. The grating periods Λ_i were chosen in the range $\Lambda_i = 370nm \dots 380nm$, with a constant grating period spacing $\Delta\Lambda = 1nm$ to result in resonances in the wavelength range $\lambda \sim 565nm - 585nm$.

20

Figure 2 schematically shows the surface refractive index scanning system 100 according to the invention. The system comprises a grating device 1, as discussed above in connection to figure 1. The system 100 further comprises an imaging system 110, here illustrated as a lens 112 and a cylindrical lens 114. The imaging
25 system 110 is configured to collect light from the grating device 1 and focus it onto an entrance slit 120 on an imaging spectrometer. It is noticed that the first grating region 2 and the second grating region 4 are imaged onto the same elongated line and onto the entrance slit 120 for coupling into the imaging spectrometer. Thus, the spatial distribution of light from the grating device is only
30 maintained along the longitudinal direction of the slit. By use of the imaging spectrometer (not shown), spectra for each position in the longitudinal direction of the slit may be recorded and analysed e.g. in a computer.

Figure 3 shows an embodiment of the surface refractive index scanning system
35 100 according to the invention. The embodiment relates to the grating device

shown in figure 1, and the schematic figure 2, wherein like reference numerals refer to identical or similar parts. Therefore, only differences with regards to the two previous figures are described here. This embodiment of the system uses an active grating device, i.e. a grating device comprising a light emitting material.

5 Pump light 131 for exciting the light emitting material is generated in a pump light source, which is here illustrated as a laser 130 for generating 532nm light. The skilled person will realize that the choice of pumping wavelength depends on the absorption spectrum of the light emitting material used in the grating device. Thus, the use of other pump wavelengths is also foreseen by the inventors. The
10 pump light source may, e.g., also be a flash pump source or other types of non-laser sources. The pump light 131 is coupled via a dichroic mirror 132 onto the grating device 1 to simultaneously pump the first grating region 2 and second grating region 4. To improve coupling of the pump light to the grating device 1, the pump laser light is here shown to be focused by a microscope objective 112a,
15 which is also used to collect and collimate the emitted light 133 generated within the grating device 1. However, in other configurations, the pump light 131 and collected light 133 will have separate optical paths onto and away from the grating device 1. The collimated emitted light 133 is focused onto the entrance slit 120 of the imaging spectrometer 136 by a focusing lens 112b and the cylindrical
20 lens 114. As a convenience, a separate image of the grating device may be formed on an optional CCD array 138 (CCD1), e.g. to inspect the focus of the system. Light for the optional CCD array 138 is split off from the emitted light beam by a beam splitter 134. To use CCD1 to check focus of the system, CCD1 should be arranged in the same distance from the beam splitter 134 as the
25 entrance slit 120. The imaging spectrometer is configured such that the CCD at the spectrograph (CCD2 139) delivers an image where the horizontal direction corresponds to the wavelength of the light. The vertical direction of the image on CCD2 139 corresponds to the longitudinal position along the entrance slit. A function generator 140 is used to generate trigger signals for the pump laser 130
30 and the imaging spectrometer 136, in particular CCD2 139.

In an example device, the grating device surface emits very narrow laser lines of approx. 0.2 nm full width at half maximum. With the spectrometer used for demonstration by the inventors, the horizontal width of the CCD2 139 will

correspond to 55 nm. Thus, several laser lines are well distinguishable on the CCD2 139 image.

The spectrometer CCD signal is analysed and a central emission wavelength is
5 found for each resonance peak/laser line e.g. by using a centre of mass algorithm
or fitting a function to the data. The central wavelength of all resonance peaks is
monitored and wavelength shifts are calculated with a computer. Wavelength
shifts correspond to refractive index changes. An image of the surface refractive
index may then be generated by the computer.

10

According to a demonstration example the optical system is capable of operating
with a frame rate of 12 Hz, limited by the read-out time of the spectrometer CCD2
139. By continuously taking images the wavelength shift of each line can be
calculated and refractive index changes can be monitored in time and space. In
15 order to demonstrate the functionality of the laser imaging system, the inventors
have added a piece of sugar to a microfluidic well with water on top of a grating
device, and used the system to monitor how the wavelength of all laser lines was
shifting upon the presence of small sugar molecules increasing the refractive
index.

20

Figure 4 shows an alternative embodiment of the surface refractive index
scanning system according to the invention, wherein the grating device 1 is a
passive device, i.e. not comprising a light emitting material. The embodiment has
many similarities with the embodiment shown in figure 3 and discussed above.
25 Therefore, only differences between the two embodiments will be discussed here.
The grating device 1 is configured to be a guided mode resonance filter. A
broadband light source is used for illumination, e.g. a Xenon lamp or an LED. In
this case, the resonant wavelengths of the grating regions 2, 4 should be
configured to fall within the emission band of the light source. Light reflected from
30 the passive photonic crystal enters into the imaging spectrometer 136 via the
cylindrical lens 114 and entrance slit 120, as described above for other
embodiments.

Figure 5 shows an alternative embodiment of the surface refractive index
35 scanning system according to the invention, wherein the grating device 1 is a

passive device. The embodiment has many similarities with the embodiment shown in figure 3 and discussed above. Therefore, only differences between the two embodiments will be discussed here. The grating device 1 is configured to be a cavity end mirror, the other end of the cavity being formed by mirror 152.

5 Within the cavity, an active element 150 is disposed so as to provide optical gain to light resonant in the cavity. Examples of an active element 150 may be a semiconductor optical amplifier (SOA), a gain crystal, or an organic dye in solution. The active element 150 is here illustrated to be optically pumped by the pump source 130. However, in other embodiments, the active element 150 could
10 alternatively be electrically pumped, depending on the choice of material. In this case the resonant wavelengths of the grating regions 2, 4 should be configured to fall within the amplified spontaneous emission spectrum of the active material. A small fraction of the cavity light is coupled out via a beam splitter 134, and entered into the imaging spectrometer 136 via the cylindrical lens 114 and
15 entrance slit 120, as described above for other embodiments.

Although the present invention has been described in connection with the specified embodiments, it should not be construed as being in any way limited to
20 the presented examples. For instance, the embodiments have shown the use of a cylindrical lens as the optical element for focusing the light from the sample onto the entrance slit of the imaging spectrometer. However, the use of a bended mirror, or another optical element, for this purpose is also envisioned by the inventors and fall within the scope of the invention. The scope of the present
25 invention is set out by the accompanying claim set. In the context of the claims, the terms "comprising" or "comprises" do not exclude other possible elements or steps. Also, the mentioning of references such as "a" or "an" etc. should not be construed as excluding a plurality. The use of reference signs in the claims with respect to elements indicated in the figures shall also not be construed as limiting
30 the scope of the invention. Furthermore, individual features mentioned in different claims, may possibly be advantageously combined, and the mentioning of these features in different claims does not exclude that a combination of features is not possible and advantageous.

CLAIMS

1. A surface refractive index scanning system for characterization of a sample comprising:
 - 5 - a grating device for receiving the sample, the device comprising at least a first grating region having a first grating width along a transverse direction, and a second grating region having a second grating width in the transverse direction, the first grating region and the second grating region being adjacent in the transverse direction, wherein the first grating region has a grating
10 period Λ_1 in a longitudinal direction, the longitudinal direction being orthogonal to the transverse direction, and the second grating region has a grating period Λ_2 in the longitudinal direction, a grating period spacing $\Delta\Lambda = \Lambda_1 - \Lambda_2$ being finite, the first and second grating periods are chosen to provide optical
15 wavelength band, light is being emitted, transmitted, or reflected in an out-of-plane direction, wherein the first wavelength band and the second wavelength band are at least partially non-overlapping in wavelength,
- a light source for illuminating at least a part of the grating device with light at an illumination wavelength band,
20 - an imaging system for imaging the emitted, transmitted or reflected light from the grating device, the imaging system comprising an optical element, configured for focusing light in a first transverse direction and for being invariant in an orthogonal transverse direction, the optical element being oriented such that the longitudinal direction of the grating device is oriented to
25 coincide with an invariant direction of the optical element, and an imaging spectrometer comprising an entrance slit having a longitudinal direction oriented to coincide with the invariant direction of the optical element, the imaging spectrometer further comprising a 2-dimensional image sensor.
- 30 2. The surface refractive index scanning system according to claim 1, wherein the optical element is a cylindrical lens.
3. The surface refractive index scanning system according to claim 1, wherein the optical element is a bended mirror.

4. The surface refractive index scanning system according to any one of the preceding claims, wherein the grating device comprises multiple structured regions, including the first grating region and the second grating region, such as a number of structured regions in the range 2-100, or 10-80, or even 20-50, wherein each of the grating regions are arranged to provide optical resonances for light respectively in corresponding wavelength bands, light is being emitted, transmitted, or reflected in an out-of-plane direction, the corresponding wavelength bands being at least partially non-overlapping.
5. The surface refractive index scanning system according to any one of the previous claims, wherein the first structured region and/or the second structured region are configured as a second order distributed Bragg reflector (DBR) for providing the optical resonance.
6. The surface refractive index scanning system according to any one of the preceding claims, wherein the grating device comprises a light-emitting material having an emission spectrum, wherein first structured region and the second structured region are configured such that the first wavelength range and the second wavelength range at least partially fall within the emission spectrum of the light-emitting material.
7. The surface refractive index scanning system according to claim 6, wherein the grating period spacing $\Delta\lambda$ between two adjacent grating regions is in the range 0.05nm-10nm, such as in the range 0.1nm-5nm, or even in the range 0.5nm-2nm.
8. The surface refractive index scanning system according to any one of claims 6-7, wherein the light-emitting material is or comprises a dye-doped material.
9. The surface refractive index scanning system according to claim 8, wherein the dye-doped material comprises a polymer.
10. The surface refractive index scanning system according to any one of claims 1-5 where the grating device is a passive structure for reflecting or transmitting light in the wavelength ranges.

11. The surface refractive index scanning system according to claim 10, wherein the grating period spacing $\Delta\Lambda$ between two adjacent grating regions is in the range 0.5nm-500nm, such as about 5nm-200nm, or even in the range 10nm-100nm.

5

12. The surface refractive index scanning system according to any one of claims 10-11, wherein the system further comprises an optical gain material and a first cavity end reflector, and wherein the grating device is arranged as a second cavity end reflector, the gain material being disposed between the first
10 cavity end reflector and the second cavity end reflector in an external cavity laser configuration.

13. The surface refractive index scanning system according to any one of the preceding claims, wherein the system is or comprises a microscope system.

15

14. A method of acquiring a surface refractive index image of a sample, the method comprising:

- providing a grating device for receiving the sample, the device comprising at least a first grating region having a first grating width
20 along a transverse direction, and a second grating region having a second grating width in the transverse direction, the first grating region and the second grating region being adjacent in the transverse direction, wherein the first grating region has a grating period Λ_1 in a longitudinal direction, the longitudinal direction being orthogonal to the transverse direction, and the second grating region has a grating period
25 Λ_2 in the longitudinal direction, a grating period spacing $\Delta\Lambda = \Lambda_1 - \Lambda_2$ being finite, wherein the first and second grating periods are chosen to provide optical resonances for light respectively in a first wavelength band and a second wavelength band, light is being emitted,
30 transmitted, or reflected in an out-of-plane direction, wherein the first wavelength band and the second wavelength band are at least partially non-overlapping in wavelength,
- positioning the sample to be characterized onto the grating device so as to come into contact with the first and/or the second grating region,

- illuminating at least a part of the grating device with light at an illumination wavelength band,
 - imaging the emitted, transmitted or reflected light from the grating device with an imaging system into a 2-dimensional raw image, the
5 imaging system comprising an optical element, configured for focusing light in a first transverse direction and for being invariant in an orthogonal transverse direction, the optical element being oriented such that the longitudinal direction of the grating device is oriented to coincide with an invariant direction of the optical element, and an
10 imaging spectrometer comprising an entrance slit having a longitudinal direction oriented to coincide with the invariant direction of the optical element, the imaging spectrometer further comprising a 2-dimensional image sensor, oriented along the longitudinal direction of the entrance slit,
 - processing the 2-dimensional raw image to obtain a 2-dimensional map
15 of refractive index change of the sample at the grating regions, by utilizing that each row of pixels in the raw image perpendicular to the longitudinal direction of the entrance slit contains spectrally resolved resonance peaks for each grating region, each resonance peak
20 corresponding to a position along the transverse direction of the grating device, and positions in the raw image along the longitudinal direction translates directly to positions along the longitudinal direction of the grating device.
- 25 15. The method according to claim 14 wherein the step of processing the image comprises tracking changes in spectral positions of the resonance peaks to provide a time-resolved image of refractive index changes in the sample.
16. The method according to claim 14 or 15, wherein processing the 2-dimensional
30 raw image comprises:
- for each row of pixels perpendicular to the longitudinal direction of the entrance slit, detect peak positions in pixels for resonance peaks in the row associated with each grating region,
 - convert each peak position in pixels to a peak wavelength value of
35 resonance,

- calculate a wavelength shift for each of the peak wavelength values of resonance with regards to reference peak values corresponding to the grating device without the sample present, and
- calculate refractive index values from the wavelength shifts.

5

17. The method according to claim 16, wherein finding the peak position in pixels for each of the grating region comprises:

- finding a peak pixel as a pixel with a highest intensity reading within a range of pixels associated with that grating region,
- 10 - calculate the peak position in pixels from a range of pixels around the peak pixel using a numerical method.

18. The method according to claim 17, wherein the numerical method is a center of mass calculation or a Lorentzian fit.

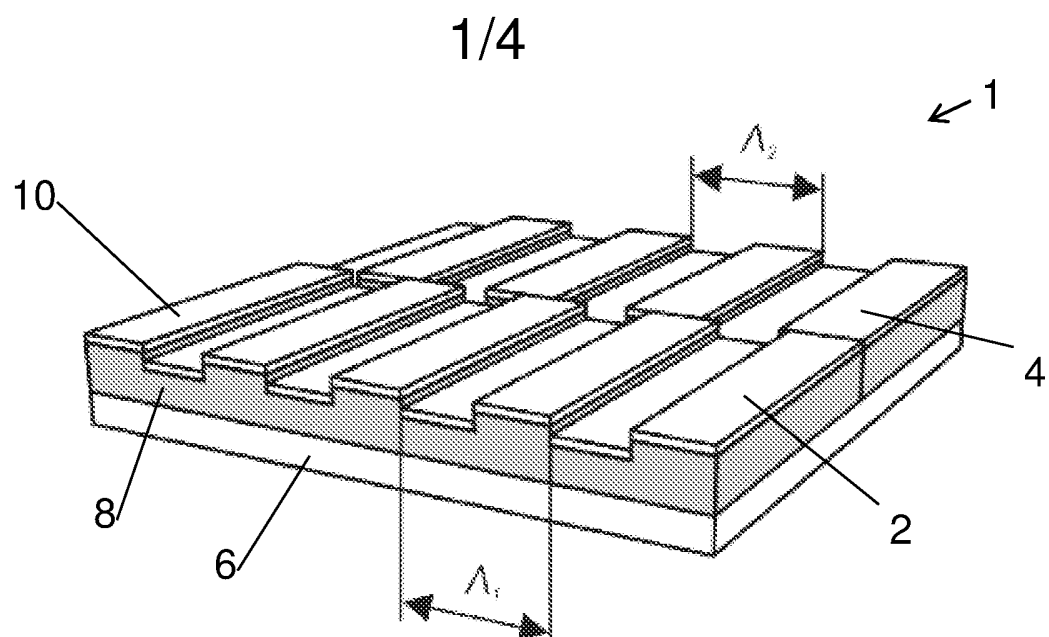


FIG. 1

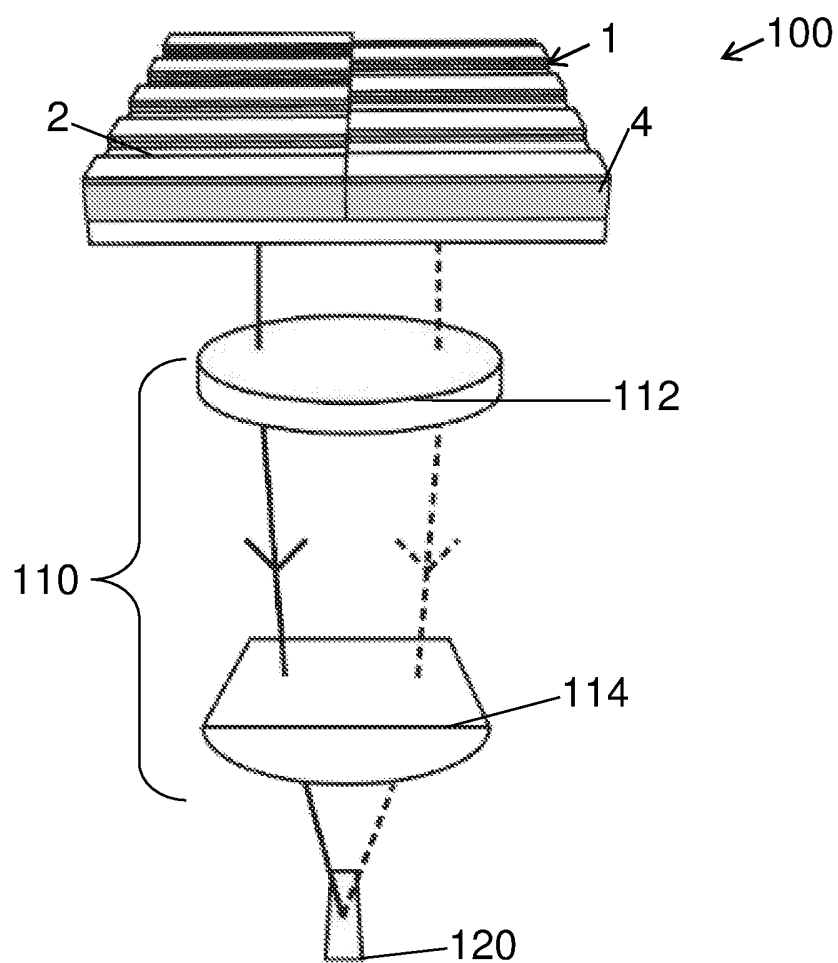


FIG. 2

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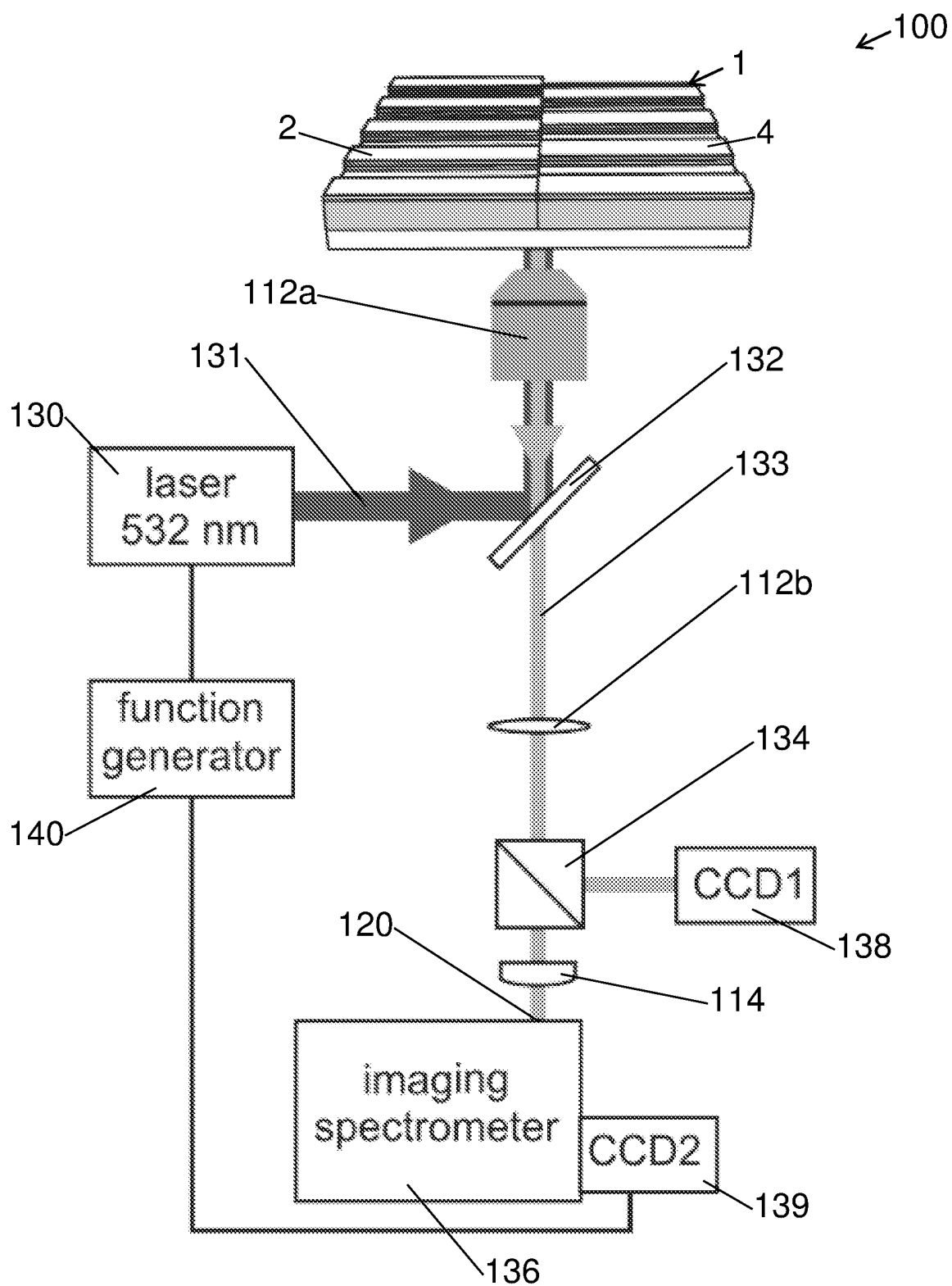


FIG. 3

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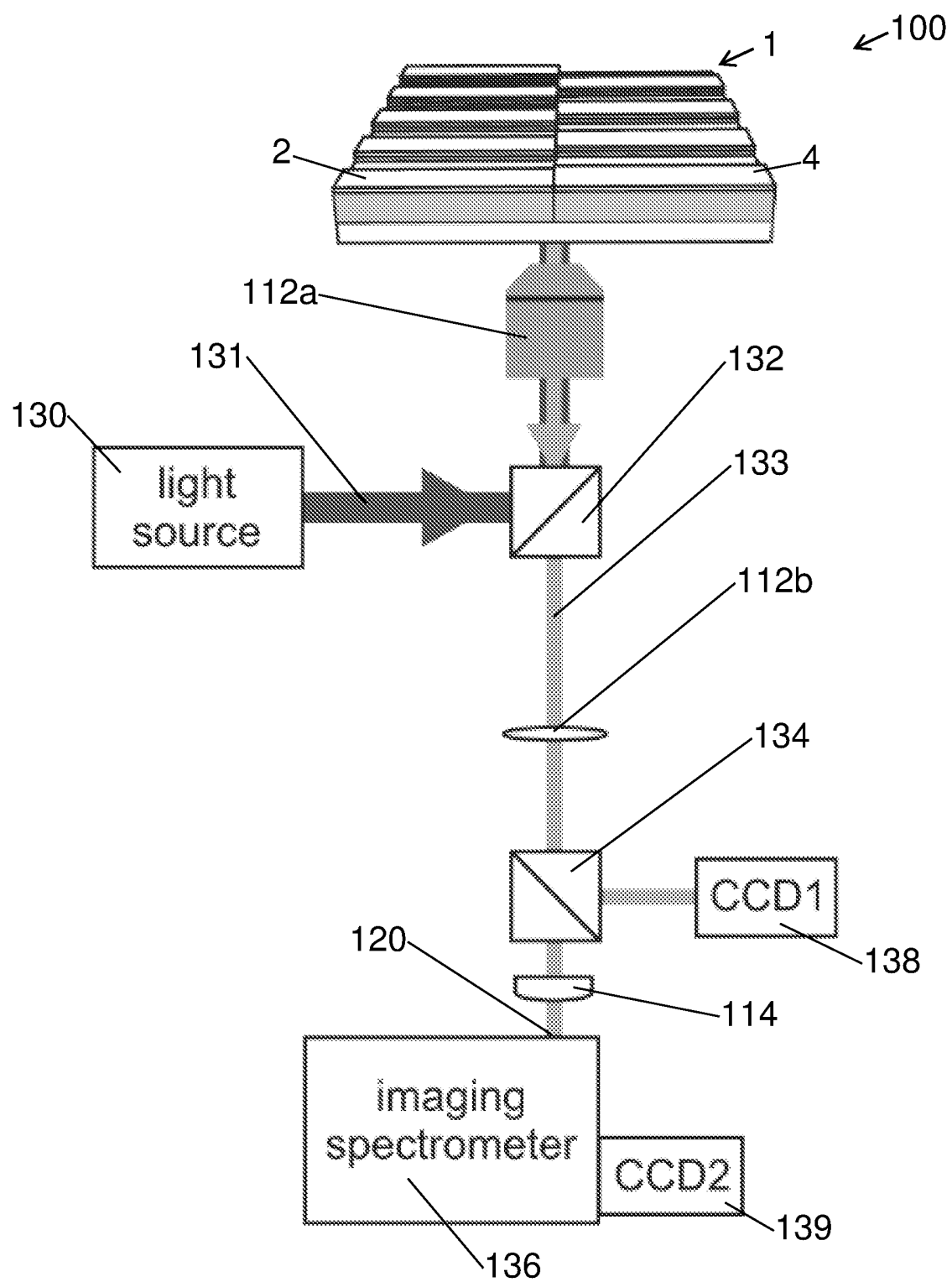


FIG. 4

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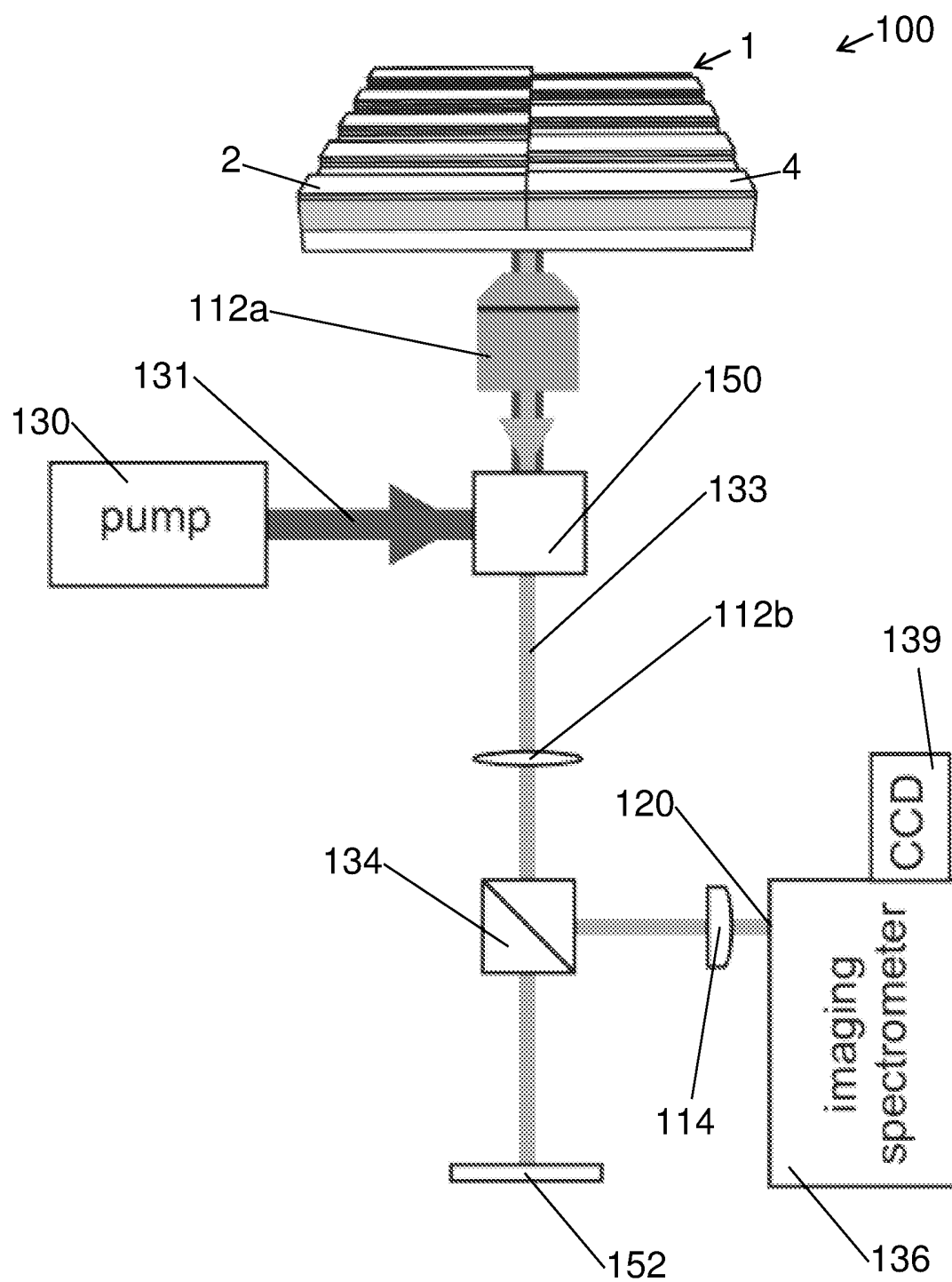


FIG. 5

INTERNATIONAL SEARCH REPORT

International application No

PCT/DK2015/050121

A. CLASSIFICATION OF SUBJECT MATTER		
INV. G01N21/77 G01J3/02 H01S5/00	G02F1/39 G01J3/06	H01S3/06 G01J3/18 H01S3/08 G01J3/28 H01S3/16 G02B6/122
According to International Patent Classification (IPC) or to both national classification and IPC		
B. FIELDS SEARCHED		
Minimum documentation searched (classification system followed by classification symbols) G02F G01N H01S G01J G02B		
Documentation searched other than minimum documentation to the extent that such documents are included in the fields searched		
Electronic data base consulted during the international search (name of data base and, where practicable, search terms used) EPO-Internal, WPI Data, INSPEC, BIOSIS		
C. DOCUMENTS CONSIDERED TO BE RELEVANT		
Category*	Citation of document, with indication, where appropriate, of the relevant passages	Relevant to claim No.
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<input checked="" type="checkbox"/> Further documents are listed in the continuation of Box C. <input checked="" type="checkbox"/> See patent family annex.		
* Special categories of cited documents :		
"A" document defining the general state of the art which is not considered to be of particular relevance "E" earlier application or patent but published on or after the international filing date "L" document which may throw doubts on priority claim(s) or which is cited to establish the publication date of another citation or other special reason (as specified) "O" document referring to an oral disclosure, use, exhibition or other means "P" document published prior to the international filing date but later than the priority date claimed		"T" later document published after the international filing date or priority date and not in conflict with the application but cited to understand the principle or theory underlying the invention "X" document of particular relevance; the claimed invention cannot be considered novel or cannot be considered to involve an inventive step when the document is taken alone "Y" document of particular relevance; the claimed invention cannot be considered to involve an inventive step when the document is combined with one or more other such documents, such combination being obvious to a person skilled in the art "&" document member of the same patent family
Date of the actual completion of the international search 1 July 2015		Date of mailing of the international search report 13/07/2015
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C(Continuation). DOCUMENTS CONSIDERED TO BE RELEVANT

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